SLLS212B - SEPTEMBER 1995 - REVISED APRIL 1998

- Bidirectional Transceiver With Fail-Safe
 Receiver
- Meets or Exceeds the Requirements of ITU Recommendation V.11
- Electrically Compatible With ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A
- Designed for Multipoint Transmission on Long Bus Lines in Noisy Environments
- 3-State Driver and Receiver Outputs
- Individual Driver and Receiver Enables
- Wide Positive and Negative Input/Output
 Bus Voltage Ranges
- Driver Output Capability . . . ±60 mA Max
- Thermal Shutdown Protection
- Driver Positive and Negative Current Limiting
- Receiver Input Impedance . . . 12 kΩ Min
- Receiver Input Sensitivity . . . 300 mV/0 mV
- Operates From Single 5-V Supply
- Pin-to-Pin Compatible With SN75176A

description

The SN75276 differential bus transceiver is a monolithic, integrated circuit designed for bidirectional data communication on multipoint bus transmission lines. It is designed for balanced transmission lines and is electrically compatible with ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A, and meets ITU Recommendation V.11.

The fail-safe operation ensures a known level on the circuit output under bus fault conditions. The circuit provides a high-level output under floating-line, idle-line, open-circuit, and short-circuit bus conditions (see Function Tables).

The SN75276 combines a 3-state, differential line driver and a differential input line receiver, both of which operate from a single, 5-V power supply. The driver and receiver have active-high and active-low enables, respectively, that can be externally connected together to function as a direction control. The driver differential outputs and the receiver differential inputs are connected internally to form differential input/output (I/O) bus ports that are designed to offer minimum loading to the bus whenever the driver is disabled or $V_{CC} = 0$. These ports feature wide positive and negative common-mode voltage ranges making the device suitable for party-line applications.

The driver is designed for up to 60 mA of sink or source current. The driver features positive- and negative-current limiting and thermal shutdown for protection from line fault conditions. Thermal shutdown is designed to occur at a junction temperature of approximately 150°C. The receiver features a minimum input impedance of $12 \text{ k}\Omega$.

The SN75276 can be used in transmission line applications employing the SN75172 and SN75174 quadruple differential line drivers and SN75173 and SN75175 quadruple differential line receivers.

SN75276 is characterized for operation from 0°C to 70°C.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





SLLS212B - SEPTEMBER 1995 - REVISED APRIL 1998

Function Tables

EACH DRIVER

INPUT	ENABLE	OUTI	PUTS
D	DE	Α	В
Н	Н	Н	L
L	Н	L	Н
Х	L	Z	Z

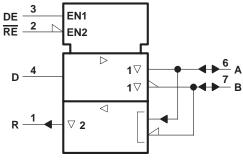
EACH RECEIVER

DIFFERENTIAL A – B	ENABLE RE	OUTPUT R
V _{ID} ≥ 0 V	L	Н
$-0.3 \text{ V} < \text{V}_{\text{ID}} < 0 \text{ V}$	L	?
V _{ID} ≤ -0.3	L	L
X	Н	Z
Open	L	Н

H = high level, L = low level, ? = indeterminate,

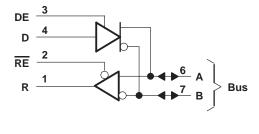
X = irrelevant, Z = high impedance (off)

logic symbol†



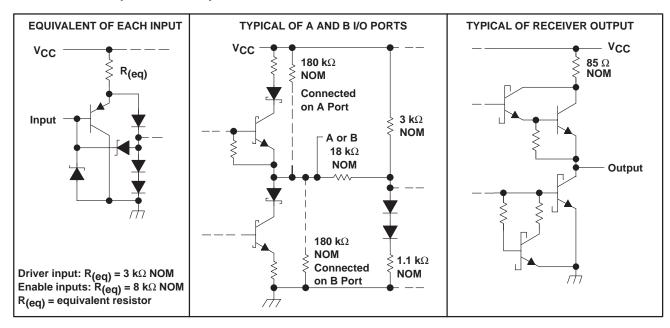
[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC} (see Note 1)	
Voltage at any bus terminal	
Enable input voltage, V ₁	
Continuous total power dissipation	See Dissipation Rating Table
Storage temperature range, T _{stq}	– 65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 105°C POWER RATING
D	725 mW	5.8 mW/°C	464 mW	261 mW
Р	1100 mW	8.8 mW/°C	704 mW	396 mW



NOTE 1: All voltage values, except differential input/output bus voltage, are with respect to network ground terminal.

SN75276 FAIL-SAFE DIFFERENTIAL BUS TRANSCEIVER

SLLS212B – SEPTEMBER 1995 – REVISED APRIL 1998

recommended operating conditions

		MIN	TYP	MAX	UNIT
Supply voltage, V _{CC}		4.75	5	5.25	V
Voltage at any hus terminal (separately o	oltage at any bus terminal (separately or common mode), V _I or V _{IC}			12	٧
7 1 10				-7	V
High-level input voltage, V _{IH}	D, DE, and RE	2			V
Low-level input voltage, V _{IL}	D, DE, and RE			0.8	V
Differential input voltage, V _{ID} (see Note 2	Differential input voltage, V _{ID} (see Note 2)			±12	V
High-level output current, IOH	Driver			-60	mA
High-level output current, IOH	Receiver			-400	μΑ
Low-level output current, IOI	Driver			60	mA
Low-level output culterit, IOL	Receiver			8	IIIA
Operating free-air temperature, TA		0		70	°C

NOTE 2: Differential input/output bus voltage is measured at the noninverting terminal A with respect to the inverting terminal B.

SLLS212B - SEPTEMBER 1995 - REVISED APRIL 1998

DRIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONI	OITIONS [†]	MIN	TYP [‡]	MAX	UNIT
VIK	Input clamp voltage	I _I = -18 mA				-1.5	V
٧o	Output voltage	IO = 0		0		6	V
VOD1	Differential output voltage	IO = 0		1.5	3.6	6	V
IVonal	Differential output voltage	$R_L = 100 \Omega$,	See Figure 1	1/2 V _{OD1} or	2§		V
IV _{OD2} I	Differential output voltage	$R_L = 54 \Omega$,	See Figure 1	1.5	2.5	5	V
V _{OD3}	Differential output voltage	See Note 3		1.5		5	V
ΔIVODI	Change in magnitude of differential output voltage \P					±0.2	V
Voc	Common-mode output voltage	R_L = 54 Ω or 100 Ω , See Figure 1	See Figure 1			+3 -1	V
∆IVocI	Change in magnitude of common-mode output voltage¶					±0.2	V
la.	Output ourront	Output disabled,	V _O = 12 V			1	mA
Ю	Output current	See Note 4	$V_O = -7 V$			-0.8	IIIA
lН	High-level input current	V _I = 2.4 V				20	μΑ
Iμ	Low-level input current	V _I = 0.4 V				-400	μΑ
		$V_0 = -7 V$				-250	
loo	Chart size it suttout surrent	V _O = 0				150	mA
los	Short-circuit output current	AO = ACC				250	IIIA
		V _O = 12 V				250	
loo	Supply current (total package)	No load	Outputs enabled		42	70	mA
Icc	Supply culteric (total package)	No load	Outputs disabled		26	35	IIIA

[†] The power-off measurement in ANSI Standard TIA/EIA-422-B applies to disabled outputs only and is not applied to combined inputs and outputs.

switching characteristics, V_{CC} = 5 V, R_L = 110 k Ω , T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t _d (OD)	Differential-output delay time	R _L = 54 Ω,	See Figure 3		15	22	ns
t _t (OD)	Differential-output transition time		See Figure 5		20	30	ns
t _{PZH}	Output enable time to high level	See Figure 4			85	120	ns
tPZL	Output enable time to low level	See Figure 5			40	60	ns
tPHZ	Output disable time from high level	See Figure 4			150	250	ns
tPLZ	Output disable time from low level	See Figure 5			20	30	ns



[‡] All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

[§] The minimum V_{OD2} with a 100-Ω load is either 1/2 V_{OD1} or 2 V, whichever is greater.

[¶] $\Delta |V_{OD}|$ and $\Delta |V_{OC}|$ are the changes in magnitude of V_{OD} and V_{OC} , respectively, that occur when the input is changed from a high level to a low level.

NOTES: 3. This applies for both power on and off; refer to TIA/EIA-485-A for exact conditions. The TIA/EIA-422-B limit does not apply for a combined driver and receiver terminal.

^{4.} See TIA/EIA-485-A Figure 3.5, Test Termination Measurement 2.

DRIVER SECTION

SYMBOL EQUIVALENTS

DATA-SHEET PARAMETER	TIA/EIA-422-B	TIA/EIA-485-A
Vo	V _{oa} , V _{ob}	V _{oa} , V _{ob}
V _{OD1}	Vo	V _o
IV _{OD2} I	$V_t (R_L = 100 \Omega)$	$V_t (R_L = 54 \Omega)$
V _{OD3}	None	V _t (Test Termination Measurement 2)
Δ V _{OD}	$ V_t - \overline{V}_t $	$ V_t - \overline{V}_t $
Voc	V _{os}	V _{os}
Δ VOC	$ V_{OS} - \overline{V}_{OS} $	$ V_{OS} - \overline{V}_{OS} $
los	$ I_{sa} , I_{sb} $	
lo	$ I_{xa} , I_{xb} $	l _{ia} , l _{ib}

RECEIVER SECTION

electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
V _{IT+}	Positive-going input threshold voltage	V _O = 2.7 V,	$I_{O} = -0.4 \text{ mA}$			0	V
VIT-	Negative-going input threshold voltage	$V_0 = 0.5 V$,	IO = 8 mA	-0.3‡			V
٧ıĸ	Enable clamp voltage	I _I = -18 mA				-1.5	V
Vон	High-level output voltage	V _{ID} = 0, See Figure 2	$I_{OH} = -400 \mu A,$	2.7			٧
VOL	Low-level output voltage	V _{ID} = -300 mV, See Figure 2	I _{OL} = 8 mA,			0.45	٧
loz	High-impedance-state output current	$V_0 = 0.4 \text{ V to } 2.4 \text{ V}$				±20	μΑ
١.	Line input current	Other input = 0 V,	V _I = 12 V			1	mA
Η	Line input current	See Note 5	V _I = -7 V			-0.8	IIIA
ΙΗ	High-level enable input current	V _{IH} = 2.7 V				20	μΑ
IIL	Low-level enable input current	V _{IL} = 0.4 V				-100	μΑ
rį	Input resistance	V _I = 12 V		12			kΩ
los	Short-circuit output current			-15		-85	mA
laa	Supply current (total package)	No load	Outputs enabled		42	55	mA
Icc	Supply current (total package)	INO IOAU	Outputs disabled		26	35	IIIA

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

NOTE 5: This applies for both power on and power off. Refer to TIA/EIA-485-A for exact conditions.



[‡] The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for negative-going input threshold voltage levels only.

RECEIVER SECTION

switching characteristics, V_{CC} = 5 V, C_L = 15 pF, T_A = 25°C

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low- to high-level output	V _{ID} = 0 to 3 V, See Figure 6		21	35	ns
tPHL	Propagation delay time, high- to low-level output	VID = 0 to 3 V, See Figure 6		23	35	ns
tPZH	Output enable time to high level	See Figure 7		10	20	ns
tPZL	Output enable time to low level	See Figure 7		12	20	ns
tPHZ	Output disable time from high level	See Figure 7		20	35	ns
^t PLZ	Output disable time from low level	See Figure 7		17	25	ns

PARAMETER MEASUREMENT INFORMATION

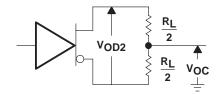


Figure 1. Driver $V_{\mbox{\scriptsize OD}}$ and $V_{\mbox{\scriptsize OC}}$

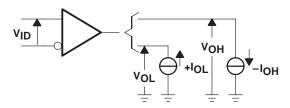
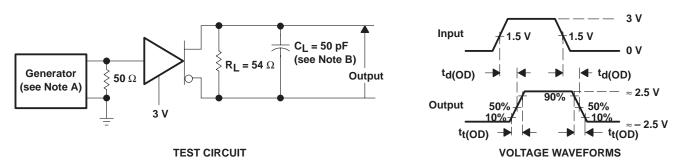


Figure 2. Receiver $V_{\mbox{OH}}$ and $V_{\mbox{OL}}$



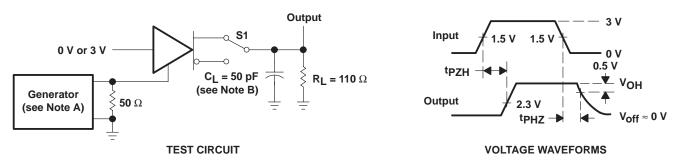
NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $t_f \leq$ 6 ns, $t_f \leq$ 7 ns, $t_f \leq$ 8 ns, t_f

B. C_L includes probe and jig capacitance.

Figure 3. Driver Test Circuit and Voltage Waveforms

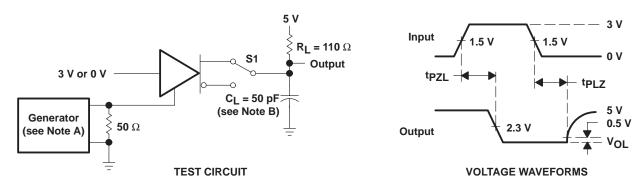


PARAMETER MEASUREMENT INFORMATION



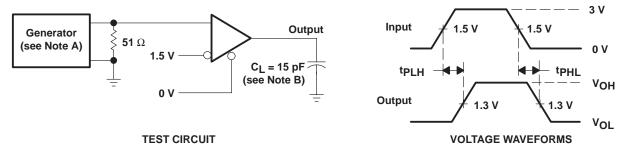
- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $t_{\Gamma} \leq$ 6 ns, $t_{\Gamma} \leq$ 7 ns, $t_{\Gamma} \leq$ 8 ns, $t_{\Gamma} \leq$ 8 ns, $t_{\Gamma} \leq$ 9 ns, $t_$
 - B. C_L includes probe and jig capacitance.

Figure 4. Driver Test Circuit and Voltage Waveforms



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $t_f \leq$ 6 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 9 ns, t_f
 - B. C_L includes probe and jig capacitance.

Figure 5. Driver Test Circuit and Voltage Waveforms

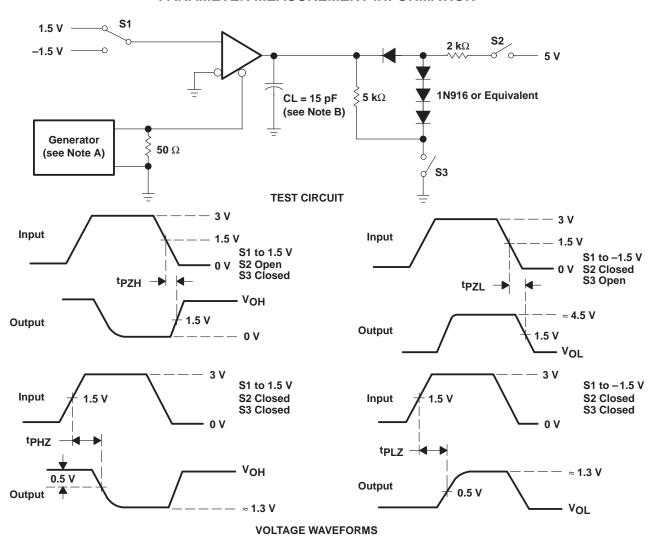


- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $t_{\Gamma} \leq$ 6 ns, $t_{\Gamma} \leq$ 7 ns, $t_{\Gamma} \leq$ 8 ns, $t_{\Gamma} \leq$ 8 ns, $t_{\Gamma} \leq$ 9 ns, $t_$
 - B. C_L includes probe and jig capacitance.

Figure 6. Receiver Test Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION



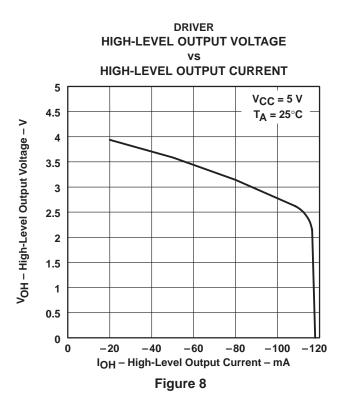
NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $t_f \leq$ 6 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 8 ns, $t_f \leq$ 9 ns, t_f

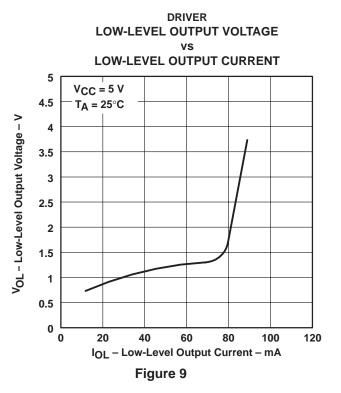
B. C_L includes probe and jig capacitance.

Figure 7. Receiver Test Circuit and Voltage Waveforms



TYPICAL CHARACTERISTICS





DRIVER DIFFERENTIAL OUTPUT VOLTAGE vs

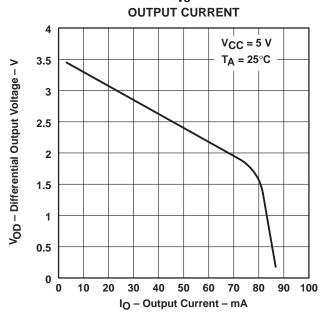


Figure 10



TYPICAL CHARACTERISTICS[†]

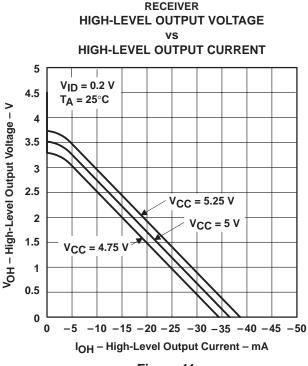


Figure 11

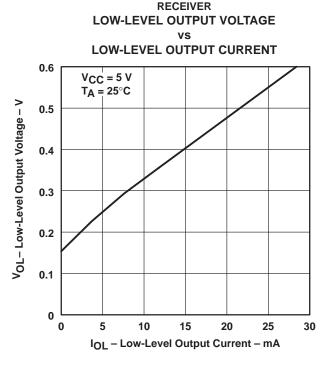


Figure 13

RECEIVER HIGH-LEVEL OUTPUT VOLTAGE FREE-AIR TEMPERATURE

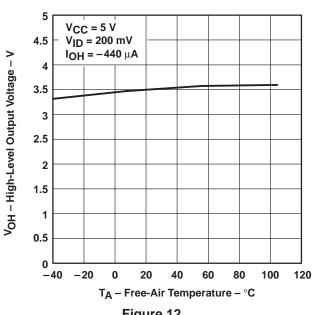


Figure 12

RECEIVER LOW-LEVEL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE

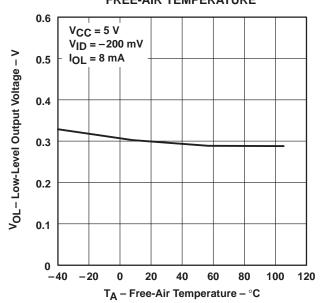
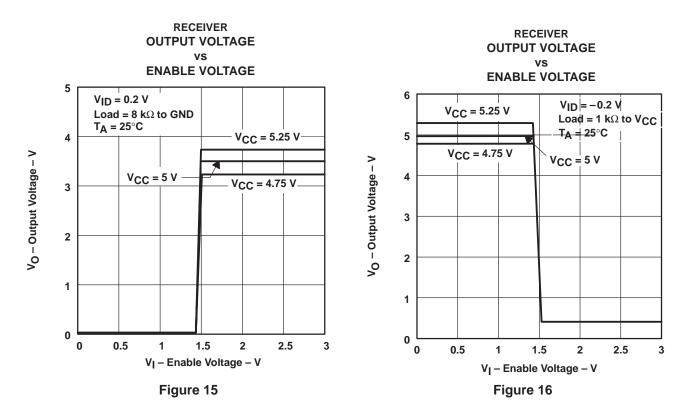


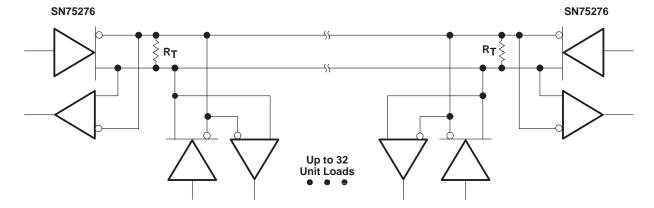
Figure 14

[†] Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

TYPICAL CHARACTERISTICS



APPLICATION INFORMATION



NOTE A: The line should be terminated at both ends in its characteristic impedance. Stub lengths off the main line should be kept as short as possible $(R_T = Z_O)$.

Figure 17. Typical Application Circuit



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